

10/583180

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Substitute for form 1449A/B/PTO INFORMATION DISCLOSURE STATEMENT BY APPLICANT <i>(Use as many sheets as necessary)</i>			Complete If Known		
			Application Number	Not Yet Assigned	
			Filing Date	Concurrently Herewith	
			First Named Inventor	Masayasu MIYATA, et al.	
			Art Unit	N/A	
			Examiner Name	Not Yet Assigned	
Sheet	1	of	1	Attorney Docket Number	9319A-001729/US/NP

U.S. PATENT DOCUMENTS					
Examiner Initials*	Cite No. ¹	Document Number Number-Kind Code ² (if known)	Publication Date MM-DD-YYYY	Name of Patentee or Applicant of Cited Document	Pages, Columns, Lines, Where Relevant Passages or Relevant Figures Appear
/NN/	AA*	US-2002/0047169-A1	04-25-2002	Kunikiyo	
	AB*	US-6,208,002-B1	03-27-2001	Satake et al.	
	AC*	US-2002/0140043-A1	10-03-2002	Mitani et al.	
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FOREIGN PATENT DOCUMENTS						
Examiner Initials*	Cite No. ¹	Foreign Patent Document	Publication Date	Name of Patentee or Applicant of Cited Document	Pages, Columns, Lines, Where Relevant Passages or Relevant Figures Appear	T ⁶
		Country Code ³ -Number ⁴ -Kind Code ⁵ (if known)	MM-DD-YYYY			
/NN/	BA	EP-0 892 424-A	01-20-1999			N/A
/NN/	BB	WO-2005/050743-A	06-02-2005			N/A
/NN/	BC	JP-2002-299612-A	10-11-2002			Abstract

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NON PATENT LITERATURE DOCUMENTS			
Examiner Initials*	Cite No. ¹	Include name of the author (in CAPITAL LETTERS), title of the article (when appropriate), title of the item (book, magazine, journal, serial, symposium, catalog, etc.), date, page(s), volume-issue number(s), publisher, city and/or country where published.	T ²
/NN/		International Search Report for PCT/JP2004/019467, dated 8/15/2005; ISA/EP	

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Examiner Signature	/Ngan Ngo/	Date Considered	12/25/2007
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Sheet 1 of 2

ATTORNEY DOCKET No.

9319A-001729/NP

SERIAL No.

10/583,180

APPLICANT

Masayasu MIYATA

FILING DATE

June 16, 2006

GROUP

2811

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1.	/NN/	5,972,765	10/26/1999	Clark et al.		
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3.		2000-150803	05/30/2000	Japan			X
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10.	/NN/	2003-347297	12/05/2003	Japan		Abstract	

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	9319A-001729/NP	10/583,180
	APPLICANT	
	Masayasu MIYATA	
	FILING DATE	GROUP
	June 16, 2006	2811

OTHER DOCUMENTS (including Author, Title, Date, Pertinent Pages, etc.)		
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1.	/NN/	G. D. Wilk et. al., 'Stable zirconium silicate gate dielectrics deposited directly on silicon', Allied Physics Letters, Volume 76, Number 1, January 3, 2000.
2.	/NN/	M. Quevedo-Lopez et. al., 'Hafnium interdiffusion studies from hafnium silicate into silicon', Applied Physics Letters, Volume 79, Number 25, 17 December 2001.
3.	/NN/	G. D. Wilk et al., 'Electrical properties of hafnium silicate gate dielectrics deposited directly on silicon', Applied Physics Letters, Volume 74, Number 19, 10 May 1999.
4.	/NN/	Shin-ichi Saito et. al., 'Inversion Electron Mobility Affected by Phase Separation in High-Permittivity Gate Dielectrics', Jpn. J. Appl. Phys., Vol. 42 (2003) pp. L1425-L1428, Part 2, No. 12A, 1 December 2003.'

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